


<b>Search Notes</b>  	<b>Application/Control No.</b>  10575262	<b>Applicant(s)/Patent Under Reexamination</b>  MURAKAMI, FUMIKI
	<b>Examiner</b>  Haidung D Nguyen	<b>Art Unit</b>  1796

SEARCHED			
Class	Subclass	Date	Examiner
252	601, 609	10/9/08	\HN\
525		10/9/08	\HN\

SEARCH NOTES		
Search Notes	Date	Examiner
inventor search in eDan and Palm	10/9/08	\HN\

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

/H. N./ Examiner.Art Unit 1796	
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